Modern Computer Vision and Image Analysis

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Message from the Guest Editors

This Special Issue aims to collect high-quality research papers on learning from limited samples and labeled data for computer vision and image processing applications (such as image classification, object detection, semantic segmentation, instance segmentation, etc.), as well as to publish new ideas, theories, solutions, and insights on the subject, and display their relevant applications.

Topics of interest in this Special Issue include but are not limited to:

- Theory of computer vision and image processing;
- Low level visual understanding and image processing;
- 3D vision and reconstruction;
- Document analysis and identification;
- Target detection, tracking and recognition;
- Behavior recognition;
- Multimedia analysis and reasoning;
- Medical image processing and analysis;
- Remote sensing image interpretation;
- Optimization and learning methods;
- Multimodal information processing;
- Performance measurement and benchmark database;
- Video analysis and understanding;
- Visual application and system.

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Special Issue

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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